

Octal D-Type Latch with 3-State Outputs

With 5 V-Tolerant Inputs

MC74LVX573

The MC74LVX573 is an advanced high speed CMOS octal latch with 3-state outputs. The inputs tolerate voltages up to 5.5 V, allowing the interface of 5.0 V systems to 3.0 V systems.

This 8-bit D-type latch is controlled by a latch enable input and an output enable input. When the output enable input is high, the eight outputs are in a high impedance state.

Features

- High Speed: $t_{PD} = 6.4 \text{ ns}$ (Typ) at $V_{CC} = 3.3 \text{ V}$
- Low Power Dissipation: $I_{CC} = 4 \mu A$ (Max) at $T_A = 25 \,^{\circ}C$
- Power Down Protection Provided on Inputs
- Balanced Propagation Delays
- Low Noise: $V_{OLP} = 0.8 \text{ V (Max)}$
- Pin and Function Compatible with Other Standard Logic Families
- Latchup Performance Exceeds 100 mA
- ESD Performance: Human Body Model > 2000 V;
- These Devices are Pb-Free and are RoHS Compliant

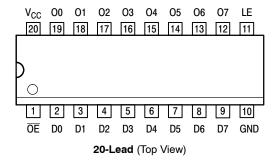




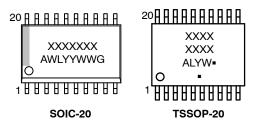


TSSOP-20 DT SUFFIX CASE 948E

PIN ASSIGNMENT



MARKING DIAGRAMS



XXXXXXX = Specific Device Code A = Assembly Location

WL, L = Wafer Lot
Y = Year
WW, W = Work Week
G or • = Pb-Free Package

(Note: Microdot may be in either location)

ORDERING INFORMATION

See detailed ordering and shipping information in the package dimensions section on page 6 of this data sheet.

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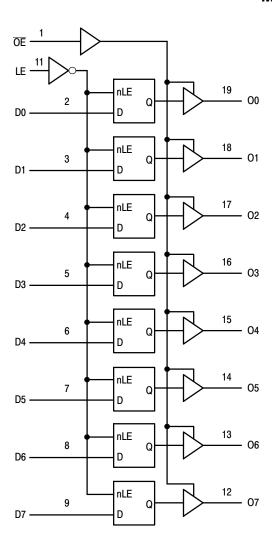


Figure 1. Logic Diagram

PIN NAMES

Pins	Function
OE	Output Enable Input
LE	Latch Enable Input
D0-D7	Data Inputs
O0-O7	3-State Latch Outputs

TRUTH TABLE

ı	INPUTS		OUTPUTS	
OE	LE	Dn	On	OPERATING MODE
L	H	H	H L	Transparent (Latch Disabled); Read Latch
L	L L	h I	H L	Latched (Latch Enabled) Read Latch
L	L	Х	NC	Hold; Read Latch
Н	L	Х	Z	Hold; Disabled Outputs
H	H	H L	Z Z	Transparent (Latch Disabled); Disabled Outputs
H	L L	h I	Z Z	Latched (Latch Enabled); Disabled Outputs

H = High Voltage Level; h = High Voltage Level One Setup Time Prior to the Latch Enable High-to-Low Transition; L = Low Voltage Level; I = Low Voltage Level One Setup Time Prior to the Latch Enable High-to-Low Transition; NC = No Change, State Prior to the Latch Enable High-to-Low Transition; X = High or Low Voltage Level or Transitions are Acceptable; Z = High Impedance State; For I_{CC} Reasons DO NOT FLOAT Inputs.

MAXIMUM RATINGS

Symbol	Pai	ameter	Value	Unit
V _{CC}	DC Supply Voltage	-0.5 to +6.5	V	
V _{IN}	DC Input Voltage		-0.5 to +6.5	V
V _{OUT}	DC Output Voltage		-0.5 to V _{CC} +0.5	V
I _{IN}	DC Input Current, per Pin		±20	mA
I _{OUT}	DC Output Current, Per Pin		±25	mA
I _{CC}	DC Supply Current, V _{CC} and GND Pins		±75	mA
I _{IK}	Input Clamp Current		-20	mA
lok	Output Clamp Current		±20	mA
T _{STG}	Storage Temperature Range	-65 to +150	°C	
TL	Lead Temperature, 1 mm from Case for 1	260	°C	
TJ	Junction Temperature Under Bias		+150	°C
$\theta_{\sf JA}$	Thermal Resistance (Note 2)	SOIC-20W	96	°C/W
		TSSOP-20	150	
P_{D}	Power Dissipation in Still Air at 25 °C	SOIC-20W	1302	mW
		TSSOP-20	833	
MSL	Moisture Sensitivity	SOIC-20W	Level 3	-
		All Other Packages	Level 1	
F _R	Flammability Rating Oxygen Index: 28 to 34		UL 94 V-0 @ 0.573 in	-
V _{ESD}	ESD Withstand Voltage (Note 3)	Human Body Model	2000	V
		Charged Device Model	N/A	
I _{LATCHUP}	Latchup Performance (Note 4)	•	±100	mA

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

- 1. Applicable to devices with outputs that may be tri-stated.
- Measured with minimum pad spacing on an FR4 board, using 76mm-by-114mm, 2-ounce copper trace no air flow per JESD51-7.
 HBM tested to EIA / JESD22-A114-A. CDM tested to JESD22-C101-A. JEDEC recommends that ESD qualification to EIA/JESD22-A115A (Machine Model) be discontinued.
- 4. Tested to EIA/JÉSD78 Class II.

RECOMMENDED OPERATING CONDITIONS

Symbol	Parameter	Min	Max	Unit
V _{CC}	DC Supply Voltage	2.0	3.6	V
VI _N	DC Input Voltage (Note 5)	0	5.5	V
V _{OUT}	DC Output Voltage (Note 5)	0	V _{CC}	V
T _A	Operating Temperature	-40	+85	°C
t _{r.} t _f	Input Rise or Fall Rate	0	100	ns/V

Functional operation above the stresses listed in the Recommended Operating Ranges is not implied. Extended exposure to stresses beyond the Recommended Operating Ranges limits may affect device reliability.

5. Unused inputs must always be tied to an appropriate logic voltage level (e.g., either GND or V_{CC}). Unused outputs must be left open.

DC ELECTRICAL CHARACTERISTICS

			V _{CC}	T,	_A = 25 °	С	T _A = -40	to 85 °C	
Symbol	Parameter	Test Conditions	V	Min	Тур	Max	Min	Max	Unit
V _{IH}	High-Level Input Voltage		2.0 3.0 3.6	1.5 2.0 2.4	- - -	- - -	1.5 2.0 2.4	- - -	V
V _{IL}	Low-Level Input Voltage		2.0 3.0 3.6	- - -	- - -	0.5 0.8 0.8		0.5 0.8 0.8	V
V _{OH}	High-Level Output Voltage (V _{in} = V _{IH} or V _{IL})	$I_{OH} = -50 \mu A$ $I_{OH} = -50 \mu A$ $I_{OH} = -4 \text{ mA}$	2.0 3.0 3.0	1.9 2.9 2.58	2.0 3.0 -	- - -	1.9 2.9 2.48	- - -	V
V _{OL}	Low-Level Output Voltage (V _{in} = V _{IH} or V _{IL})	I_{OL} = 50 μA I_{OL} = 50 μA I_{OL} = 4 mA	2.0 3.0 3.0	- - -	0.0 0.0	0.1 0.1 0.36	- - -	0.1 0.1 0.44	٧
l _{in}	Input Leakage Current	V _{in} = 5.5 V or GND	3.6	-	-	±0.1	-	±1.0	μΑ
l _{OZ}	Maximum 3-State Leakage Current	$V_{in} = V_{IL} \text{ or } V_{IH}$ $V_{out} = V_{CC} \text{ or GND}$	3.6 -	_	_	±0.2 5	- -	±2.5 -	μΑ
Icc	Quiescent Supply Current	V _{in} = V _{CC} or GND	3.6	_	_	4.0	_	40.0	μΑ

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

AC ELECTRICAL CHARACTERISTICS

				T,	_A = 25 °	С	T _A = -40	to 85 °C	
Symbol	Parameter	Test Cond	ditions	Min	Тур	Max	Min	Max	Unit
t _{PLH} , t _{PHL}	Propagation Delay LE to O	V _{CC} = 2.7 V	$C_L = 15 \text{ pF}$ $C_L = 50 \text{ pF}$	-	8.2 10.7	15.6 19.1	1.0 1.0	18.5 22.0	ns
		$V_{CC} = 3.3 \pm 0.3 \text{ V}$	C _L = 15 pF C _L = 50 pF	-	6.4 8.9	10.1 13.6	1.0 1.0	12.0 15.5	
t _{PLH} , t _{PHL}	Propagation Delay D to O	V _{CC} = 2.7 V	$C_L = 15 \text{ pF}$ $C_L = 50 \text{ pF}$		7.6 10.1	14.5 18.0	1.0 1.0	17.5 21.0	ns
		$V_{CC} = 3.3 \pm 0.3 \text{ V}$	$C_L = 15 \text{ pF}$ $C_L = 50 \text{ pF}$	- -	5.9 8.4	9.3 12.8	1.0 1.0	11.0 14.5	
t _{PZL} , t _{PZH}	Output Enable Time OE to O	$V_{CC} = 2.7 \text{ V}$ $R_L = 1 \text{ k}\Omega$	$C_L = 15 \text{ pF}$ $C_L = 50 \text{ pF}$	- -	7.8 10.3	15.0 18.5	1.0 1.0	18.5 22.0	ns
		$\begin{aligned} V_{CC} &= 3.3 \pm 0.3 \text{ V} \\ R_L &= 1 \text{ k} \Omega \end{aligned}$		- -	6.1 8.6	9.7 13.2	1.0 1.0	12.0 15.5	
t _{PLZ} , t _{PHZ}	Output Disable Time OE to O	$V_{CC} = 2.7 \text{ V}$ $R_L = 1 \text{ k}\Omega$	C _L = 50 pF	_	12.1	19.1	1.0	22.0	ns
		$\begin{aligned} V_{CC} &= 3.3 \pm 0.3 \text{ V} \\ R_L &= 1 \text{ k} \Omega \end{aligned}$	C _L = 50 pF	_	10.1	13.6	1.0	15.5	
t _{OSHL} t _{OSLH}	Output-to-Output Skew (Note 6)	$V_{CC} = 2.7 \text{ V}$ $V_{CC} = 3.3 \pm 0.3 \text{ V}$		<u>-</u> -	<u>-</u> -	1.5 1.5	-	1.5 1.5	ns

^{6.} Skew is defined as the absolute value of the difference between the actual propagation delay for any two separate outputs of the same device. The specification applies to any outputs switching in the same direction, either HIGH-to-LOW (t_{OSHL}) or LOW-to-HIGH (t_{OSLH}); parameter guaranteed by design.

TIMING REQUIREMENTS

			T _A = 25 °C		T _A = -40 to 85 °C	
Symbol	Parameter	Test Conditions	Тур	Limit	Limit	Unit
t _{w(h)}	Minimum Pulse Width, LE	V _{CC} = 2.7 V V _{CC} = 3.3 ± 0.3 V		6.5 5.0	7.5 5.0	ns
t _{su}	Minimum Setup Time, D to LE	V _{CC} = 2.7 V V _{CC} = 3.3 ± 0.3 V		5.0 3.5	5.0 3.5	ns
t _h	Minimum Hold Time, D to LE	V _{CC} = 2.7 V V _{CC} = 3.3 ± 0.3 V		1.5 1.5	1.5 1.5	ns

CAPACITIVE CHARACTERISTICS

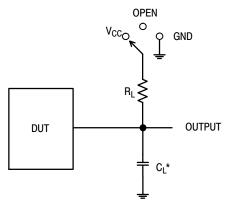
		T _A = 25 °C		T _A = -40			
Symbol	Parameter	Min	Тур	Max	Min	Max	Unit
C _{in}	Input Capacitance	-	4	10	-	10	pF
C _{out}	Maximum 3-State Output Capacitance	-	6	-	-	-	pF
C _{PD}	Power Dissipation Capacitance (Note 7)	_	29	-	_	_	pF

^{7.} C_{PD} is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load. Average operating current can be obtained by the equation: $I_{CC(OPR)} = C_{PD} \cdot V_{CC} \cdot f_{in} + I_{CC}/8$ (per latch). C_{PD} is used to determine the no-load dynamic power consumption; $P_D = C_{PD} \cdot V_{CC}^2 \cdot f_{in} + I_{CC} \cdot V_{CC}$.

NOISE CHARACTERISTICS (Input $t_{\text{r}} = t_{\text{f}} = 3.0 \text{ ns, } C_{\text{L}} = 50 \text{ pF, } V_{\text{CC}} = 3.3 \text{ V})$

		T _A = 25 °C		
Symbol	Characteristic	Тур	Max	Unit
V _{OLP}	Quiet Output Maximum Dynamic V _{OL}	0.5	8.0	V
V _{OLV}	Quiet Output Minimum Dynamic V _{OL}	-0.5	-0.8	V
V_{IHD}	Minimum High Level Dynamic Input Voltage	-	2.0	V
V_{ILD}	Maximum Low Level Dynamic Input Voltage	_	0.8	V

TEST CIRCUITS



Test	Switch Position	C _L	R _L
t _{PLH} / t _{PHL}	Open	See AC	1 kΩ
t _{PLZ} / t _{PZL}	V_{CC}	Characteristics Table	
t _{PHZ} / t _{PZH}	GND		

Figure 2. AC Test Circuit

SWITCHING WAVEFORMS

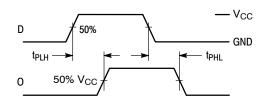


Figure 3.

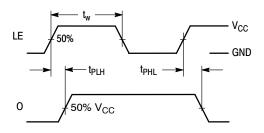


Figure 4.

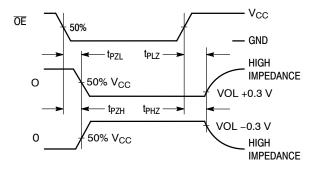


Figure 5.

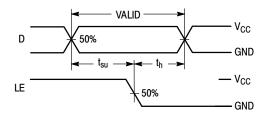


Figure 6.

ORDERING INFORMATION

Device	Marking	Package	Shipping [†]
MC74LVX573DWR2G	LVX573G	SOIC-20 WB	1000 / Tape & Reel
MC74LVX573DTG	LVX 573	TSSOP-20	75 Units / Rail
MC74LVX573DTR2G	LVX 573	TSSOP-20	2500 / Tape & Reel

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, <u>BRD8011/D.</u>

^{*}CL includes probe and jig capacitance Input $t_R = t_F = 3 \text{ ns}$

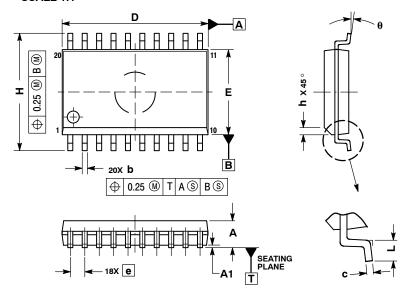




SOIC-20 WB CASE 751D-05 **ISSUE H**

DATE 22 APR 2015

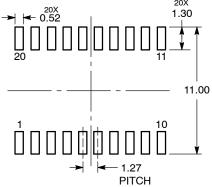
SCALE 1:1



- DIMENSIONS ARE IN MILLIMETERS.
 INTERPRET DIMENSIONS AND TOLERANCES.
- PER ASME Y14.5M, 1994.
 3. DIMENSIONS D AND E DO NOT INCLUDE MOLD PROTRUSION.
 MAXIMUM MOLD PROTRUSION 0.15 PER SIDE.
- DIMENSION B DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE PROTRUSION SHALL BE 0.13 TOTAL IN EXCESS OF B DIMENSION AT MAXIMUM MATERIAL

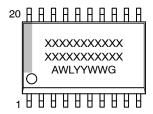
	MILLIMETERS				
DIM	MIN	MAX			
Α	2.35	2.65			
A1	0.10	0.25			
b	0.35	0.49			
С	0.23	0.32			
D	12.65	12.95			
E	7.40	7.60			
е	1.27	BSC			
Н	10.05	10.55			
h	0.25	0.75			
L	0.50	0.90			
A	0 °	7 °			

RECOMMENDED SOLDERING FOOTPRINT*



DIMENSIONS: MILLIMETERS

GENERIC MARKING DIAGRAM*



XXXXX = Specific Device Code = Assembly Location

WL = Wafer Lot ΥY = Year WW = Work Week = Pb-Free Package

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "•", may or may not be present. Some products may not follow the Generic Marking.

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^{*}For additional information on our Pb-Free strategy and soldering details, please download the onsemi Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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